

## **Session HH:**

# **Measurement of Material Properties**

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Microwave measurement techniques are used for the characterization of microwave materials and also for the measurement of the process control properties of materials. The first three papers in this session treat the measurements of the dielectric properties of a transmission media using both resonant and transmission techniques. The fourth paper presents a technique for process control measurements using a stripline resonator array. The last paper contains pulse measurement data for GaAs devices that should prove useful in the correlation of material parameters to device models.



**HH**

**10:00 a.m.–11:30 a.m., Thursday, May 10, 1990**  
**West Ballroom D**